

[54] COMBINED HANDLING, TESTING, AND SORTING MACHINE FOR INTEGRATED CIRCUITS

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[57] CLAIM

[**] Term: 14 Years

The ornamental design for a combined handling, testing, and sorting machine for integrated circuits, substantially as shown and described.

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DESCRIPTION

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[51] Int. Cl. D15-99

FIG. 1 is a perspective view of a combined handling, testing and sorting machine for integrated circuits showing my new designs;

[52] U.S. Cl. D15/147

FIG. 2 is a side elevational view taken from the right side of FIG. 1;

[58] Field of Search D15/122, 147, 199; 209/542, 543, 573; 221/266

FIG. 3 is a side elevational view taken from the left side of FIG. 1;

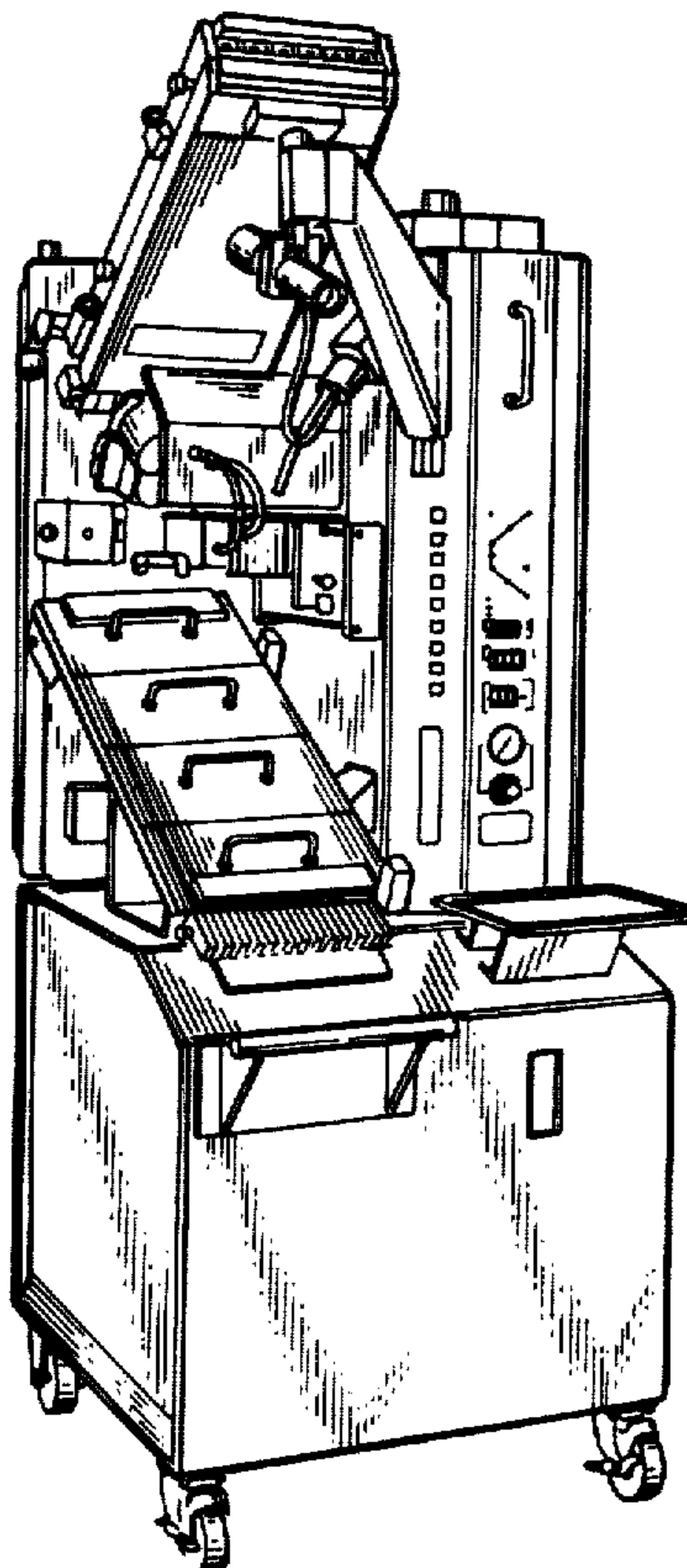
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FIG. 4 is a top plan view thereof, the bottom being unornamented; and

FIG. 5 is a rear elevational view thereof.



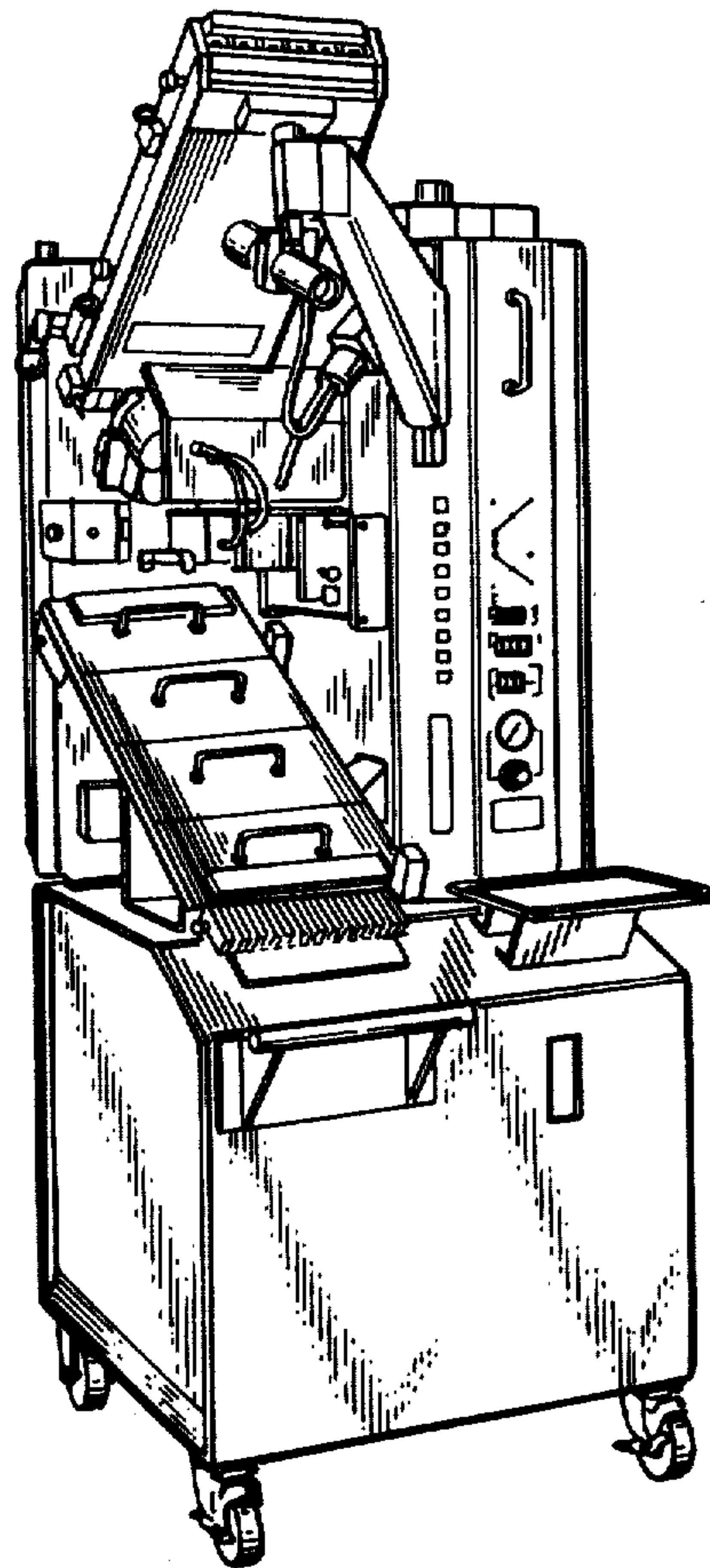


Fig. 1

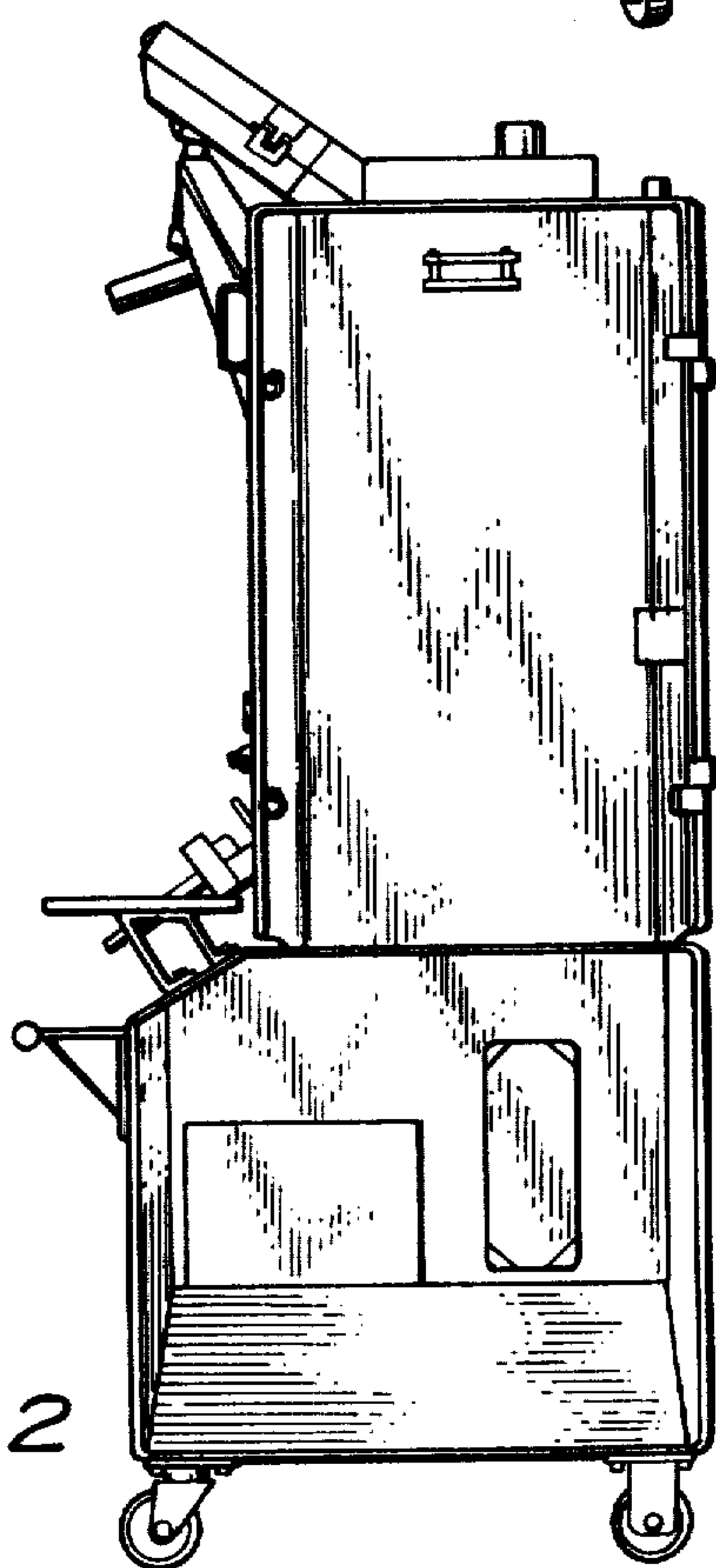


Fig. 2

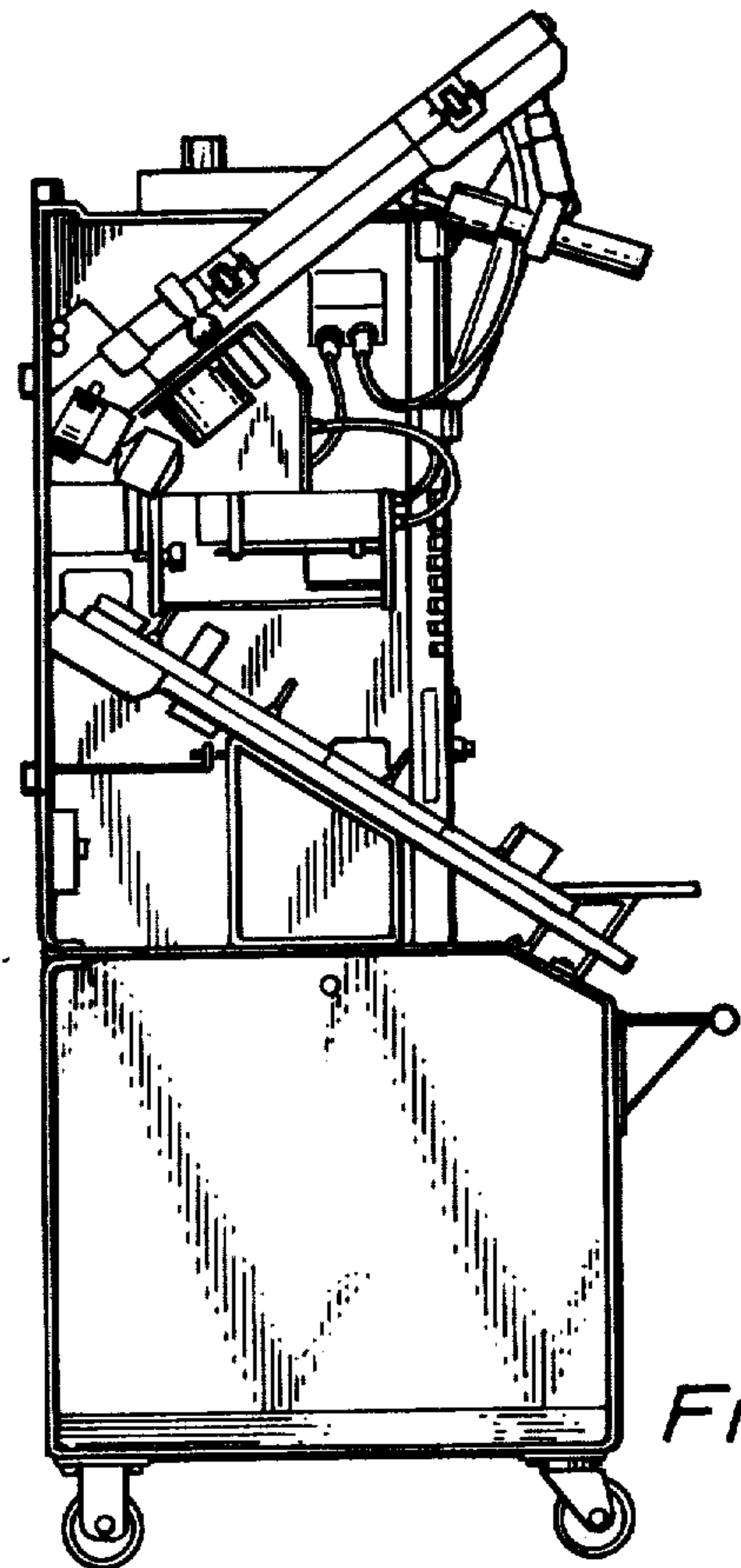


Fig. 3

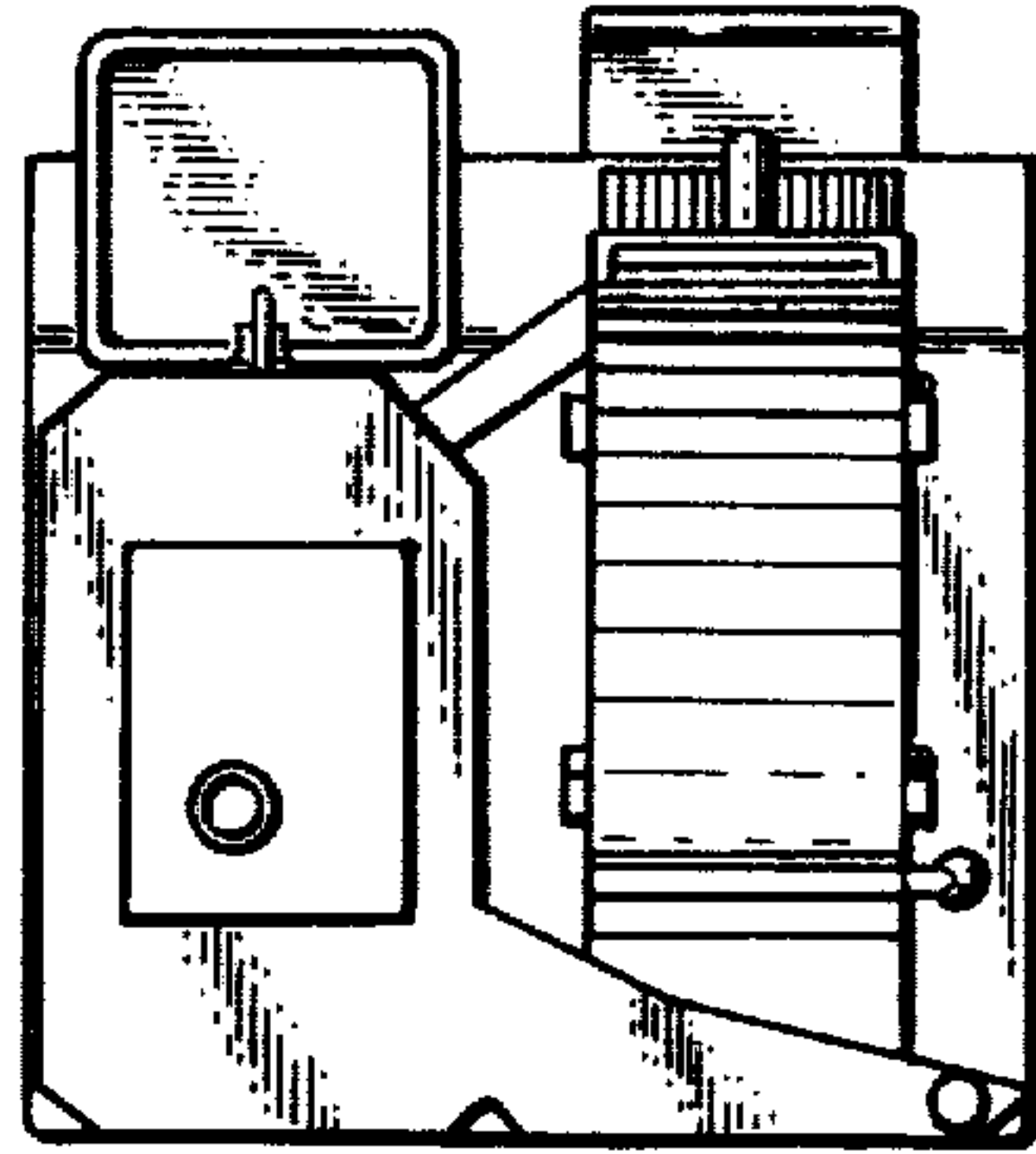


Fig. 4

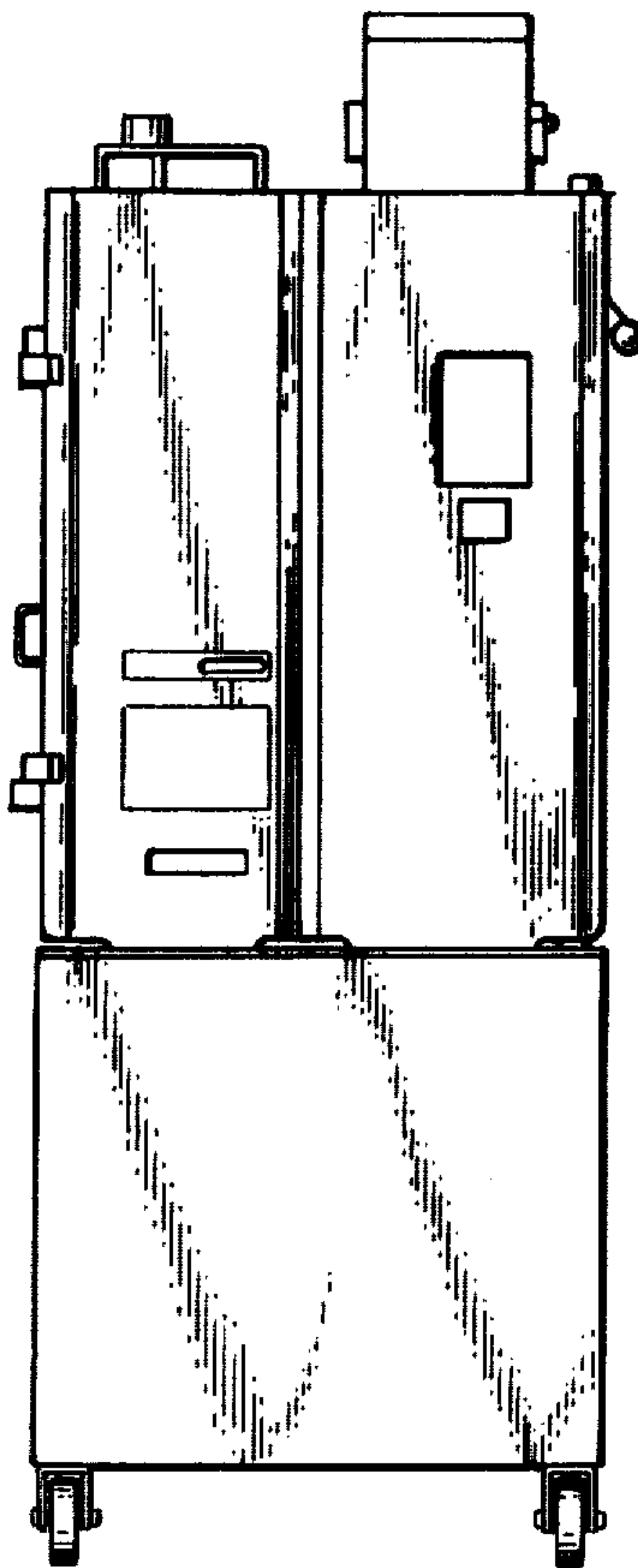


Fig. 5